# **MOSFET** – N-Channel, QFET®

100 V, 48 A, 39 m $\Omega$ 

## **FQH44N10**

## Description

This N-Channel enhancement mode power MOSFET is produced using ON Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

## **Features**

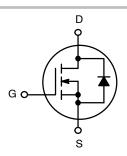
- 48 A, 100 V,  $R_{DS(on)} = 39 \text{ m}\Omega$  (Max.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 24 \text{ A}$
- Low Gate Charge (Typ. 48 nC)
- Low Crss (Typ. 85 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating



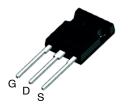
## ON Semiconductor®

### www.onsemi.com

V <sub>DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
100 V	39 mΩ @ 10 V	48 A	



**POWER MOSFET** 



TO-247-3LD CASE 340CK

#### MARKING DIAGRAM



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code

&K = Lot Code

FQH44N10 = Specific Device Code

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

## **ABSOLUTE MAXIMUM RATINGS** ( $T_C = 25^{\circ}C$ , Unless otherwise noted)

Symbol	Parameter		FQH44N10-133	Unit
V <sub>DSS</sub>	Drain-Source Voltage		100	V
I <sub>D</sub>	Drain Current	Continuous (T <sub>C</sub> = 25°C)	48	Α
		Continuous (T <sub>C</sub> = 100°C)	34	
I <sub>DM</sub>	Drain Current	Pulsed (Note 1)	192	А
V <sub>GSS</sub>	Gate-Source Voltage		±25	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		530	mJ
I <sub>AR</sub>	Avalanche Current (Note 1)		48	А
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		18	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		6.0	V/ns
$P_{D}$	Power Dissipation	(T <sub>C</sub> = 25°C)	180	W
		Derate Above 25°C	1.2	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C
TL	Maximum Lead Temperature for Soldering Purpose 1/8" from Case for 5 seconds		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 
1. Repetitive rating: pulse–width limited by maximum junction temperature. 
2. L = 0.345 mH,  $I_{AS}$  = 48 A,  $V_{DD}$  = 25 V,  $R_{G}$  = 25  $\Omega$ , starting  $T_{J}$  = 25°C. 
3.  $I_{SD} \le 43.5$  A, di/dt  $\le 300$  A/ $\mu$ s,  $V_{DD} \le BV_{DSS}$ , starting  $T_{J}$  = 25°C.

### THERMAL CHARACTERISTICS

Symbol	Parameter	FQH44N10-133	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	0.83	°C/W
R <sub>θCS</sub>	Thermal Resistance, Case-to-Sink, Typ.	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	°C/W

## PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQH44N10-133	FQH44N10	TO-247	Tube	N/A	N/A	30 Units

## FI FCTRICAL CHARACTERISTICS (To = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARACT	ERISTICS		Į.	1	•	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25 $^{\circ}$ C		0.1		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V			1	μΑ
		V <sub>DS</sub> = 80 V, T <sub>C</sub> = 150°C			10	
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 25 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -25 V, V <sub>DS</sub> = 0 V			-100	nA
ON CHARACTE	RISTICS			•		
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 24 A		0.03	0.039	Ω
9FS	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 24 A		31		S
DYNAMIC CHAI	RACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		1400	1800	pF
C <sub>oss</sub>	Output Capacitance			425	550	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	]		85	110	pF
SWITCHING CH	ARACTERISTICS			•		
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 50 \text{ V}, I_D = 43.5 \text{ A}, R_g = 25 \Omega$		19	45	ns
t <sub>r</sub>	Turn-On Rise Time	(Note 4)		190	390	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			90	190	ns
t <sub>f</sub>	Turn-Off Fall Time			100	210	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 80 V, I <sub>D</sub> = 43.5 A, V <sub>GS</sub> = 10 V		48	62	nC
Q <sub>gs</sub>	Gate-Source Charge	(Note 4)		9.0		nC
Q <sub>gd</sub>	Gate-Drain Charge			24		nC
DRAIN-SOURC	E DIODE CHARACTERISTICS AND MA	XIMUM RATINGS		•		
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				48	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				192	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 48A			1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 43.5 \text{ A},$		98		ns
Q <sub>rr</sub>	Reverse Recovery Charge	dl <sub>F</sub> /dt = 100 A/μs		360		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

### TYPICAL PERFORMANCE CHARACTERISTICS

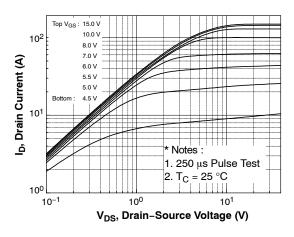


Figure 1. On-Region Characteristics

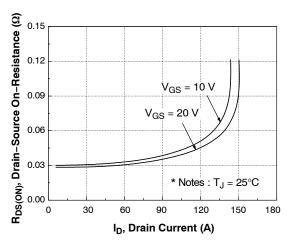


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

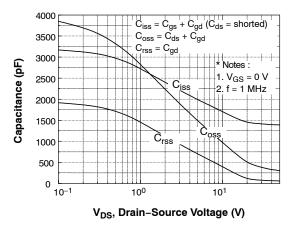


Figure 5. Capacitance Characteristics

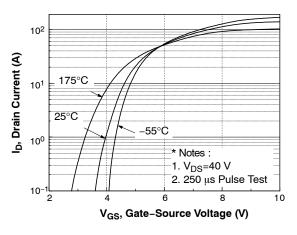


Figure 2. Transfer Characteristics

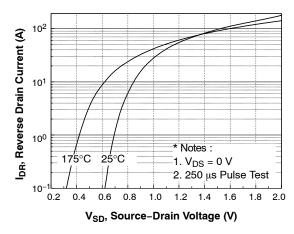


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

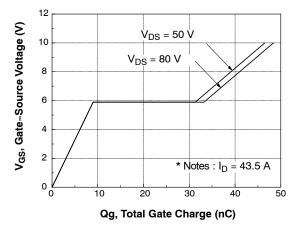


Figure 6. Gate Charge Characteristics

## TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

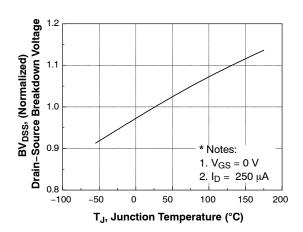


Figure 7. Breakdown Voltage Variation vs. Temperature

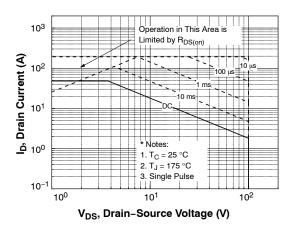


Figure 9. Maximum Safe Operating Area

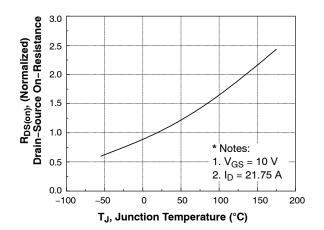


Figure 8. On–Resistance Variation vs. Temperature

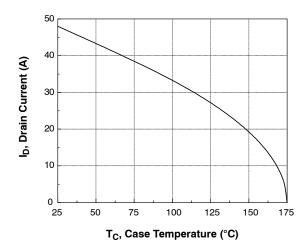
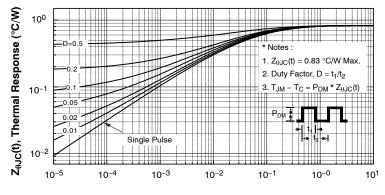


Figure 10. Maximum Drain Current vs. Case Temperature



t1, Square Wave Pulse Duration (sec)

Figure 11. Transient Thermal Response Curve

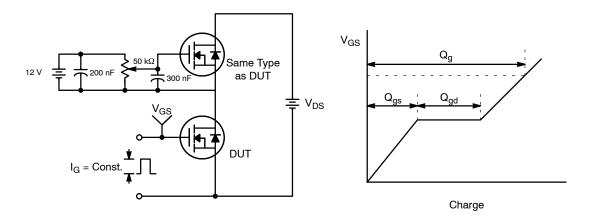


Figure 12. Gate Charge Test Circuit & Waveform

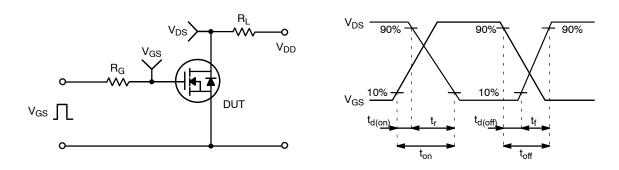


Figure 13. Resistive Switching Test Circuit & Waveforms

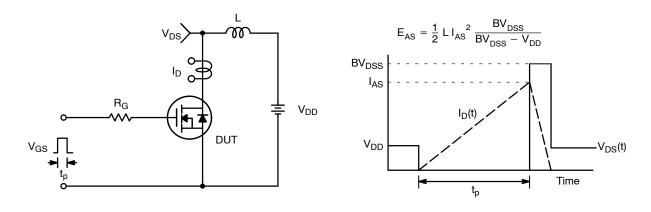


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

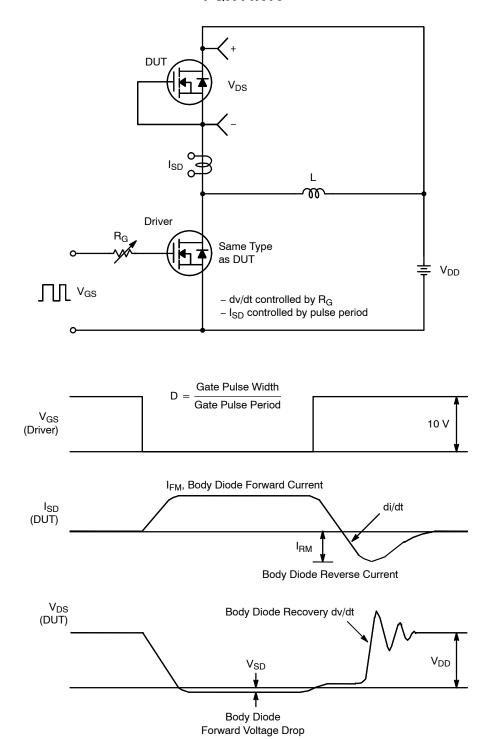


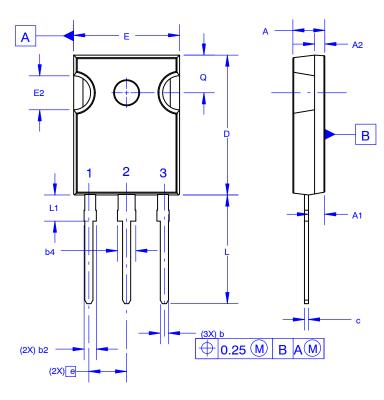
Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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#### TO-247-3LD SHORT LEAD

CASE 340CK ISSUE A



NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

## GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code

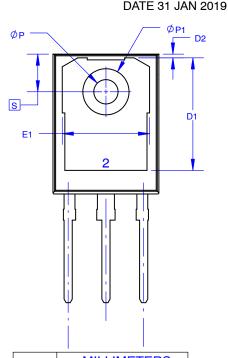
A = Assembly Location

Y = Year

WW = Work Week

ZZ = Assembly Lot Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.



DIM	MILLIMETERS				
וווט	MIN	NOM	MAX		
Α	4.58	4.70	4.82		
A1	2.20	2.40	2.60		
A2	1.40	1.50	1.60		
b	1.17	1.26	1.35		
b2	1.53	1.65	1.77		
b4	2.42	2.54	2.66		
С	0.51	0.61	0.71		
D	20.32	20.57	20.82		
D1	13.08	~	~		
D2	0.51	0.93	1.35		
Ш	15.37	15.62	15.87		
E1	12.81	~	~		
E2	4.96	5.08	5.20		
е	~	5.56	~		
L	15.75	16.00	16.25		
L1	3.69	3.81	3.93		
ØΡ	3.51	3.58	3.65		
Ø <b>P1</b>	6.60	6.80	7.00		
Q	5.34	5.46	5.58		
S	5.34	5.46	5.58		

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